

Ref #	Hits	Search Query	Dbs	Default Operator	Plurals	Time Stamp
S1	75	(324/609.ccls.) and @ad <"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 06:57
S2	165	(324/602,600.ccls.) and @ad <"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 13:21
S4	8	S1 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 current near3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 13:26
S5	18	S2 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 current near3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:51
S6	52626	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 current near3 (resist\$5 FET MOSFET BJT transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 13:00
S7	49623	S6 and @ad <"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:21
S8	327	S7 and ((capacitor sampling) near4 (resist\$5 FET MOSFET BJT transistor)) same (sampl\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:53

S9	206	S7 and ((capacitor sampling) near2 (resist\$5 FET MOSFET BJT transistor)) same (sampl\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:22
S10	18	S8 and (switch\$3 (charg\$3 adj transfer\$5)) near3 (amplifier op\$1am) near3 (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 13:24
S11	11	S9 and (switch\$3 (charg\$3 adj transfer\$5)) near3 (amplifier op\$1am) near3 (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:39
S12	3	S8 and battery near3 (charg\$3 near (level state status capacity))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:00
S13	2	S9 and battery near3 (charg\$3 near (level state status capacity))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:18
S14	504	(455/127.1.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 12:59
S15	27	S14 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 current near3 (resist\$5 FET MOSFET BJT transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 13:00

S16	911	((capacitor sampling) near2 (resist\$5 FET MOSFET BJT transistor)) same (saml\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:21
S17	878	S16 and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:38
S18	37	S17 and (switch\$3 (charg\$3 adj transfer\$5)) near3 (amplifier op\$1amp (op adj amp)) near3 (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:08
S19	5	S18 and (charg\$3 near2 (level state status capacity))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:26
S20	1	S19 and battery	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:25
S21	11544	battery near3 (charg\$3 near (level state status capacity))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:37
S22	10883	S21 and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 14:38

S23	14	S22 and ((capacitor sampling) near4 (resist\$5 FET MOSFET BJT transistor)) same (sampl\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:02
S24	1025	S7 and battery near3 (charg\$3 near (level state status capacity))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:01
S25	3	S24 and ((capacitor sampling) near4 (resist\$5 FET MOSFET BJT transistor)) same (sampl\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:07
S26	79	S24 and (capacitor sampling) same (sampl\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:08
S27	33	S26 and (switch\$3 (charg\$3 adj transfer\$5)) near3 (amplifier op\$1amp (op adj amp))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:40
S28	2	S27 and (amplifier op\$1amp (op adj amp)) near3 (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:10
S29	14	((("5769873") or ("5627740") or ("5831562") or ("5963156") or ("6285220") or ("6426657") or ("6529049")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/12 15:48

S30	3	S29 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 current near3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 15:54
S31	1	S29 and ((capacitor sampling) near4 (resist\$5 FET MOSFET BJT transistor)) same (sampl\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:23
S32	699	(327/9,55,56,337.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:05
S33	1599	(327/91-96.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 13:23
S34	77	S32 and (switch\$3 (charg\$3 adj transfer\$5)) near3 (amplifier op\$1am) near3 (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 13:26
S35	126	S33 and (switch\$3 (charg\$3 adj transfer\$5)) near3 (amplifier op\$1am) near3 (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 13:25
S36	4	S34 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 current near3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 13:27

S37	10	S35 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 current near\$3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:17
S38	209	S32 and (switch\$3 (charg\$3 adj transfer\$5)) same (amplifier op\$1am) same (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:16
S39	613	S33 and (switch\$3 (charg\$3 adj transfer\$5)) same (amplifier op\$1am) same (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 13:27
S40	11	S38 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 current near\$3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:21
S41	34	S39 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 current near\$3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:23
S42	1781	(327/50-54.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 13:58
S43	759	(341/122-125.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:20

S44	520	(341/172.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:03
S45	738	(363/76,78,89.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:03
S46	1380	(323/282,353.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:05
S47	252	S42 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 current near\$3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:13
S48	11	S43 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 current near\$3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:45
S49	12	S44 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 current near\$3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:47
S50	169	S45 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 current near\$3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:14

S51	25	S47 and (switch\$3 (charg\$3 adj transfer\$5)) same (amplifier op\$1am) same (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:16
S52	47	S50 and (switch\$3 (charg\$3 adj transfer\$5)) same (amplifier op\$1am) same (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:16
S53	11	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current) near\$3 (resist\$5 FET transistor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 14:52
S54	75	(324/609.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:15
S55	165	(324/602,600.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:16
S56	504	(455/127.1.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:16
S57	1428	(324/111,522,713.ccls.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:16

S58	11	S53 and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:51
S59	1	S58 and ((capacitor sampling) near4 (resist\$5 FET MOSFET BJT transistor)) same (sampl\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:52
S60	3	S42 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:45
S61	0	S43 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:37
S62	0	S44 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:37
S63	0	S45 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:38
S64	1	S32 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:49

S65	2	S33 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identit\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:43
S66	0	S54 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identit\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:40
S67	1	S55 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identit\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:49
S68	0	S56 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identit\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:41
S69	0	S57 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identit\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:41
S70	344	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identit\$7) near3 ((bi\$1direction\$3 ((two both) adj (way direction))) near2 current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 06:54
S71	318	S70 and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 15:51

S72	1	S71 and ((capacitor sampling) near4 (resist5 FET MOSFET BJT transistor)) same (sampil3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 06:59
S73	6	S71 and (capacitor sampling) same (sampil3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 07:00
S74	344	(check3 detect3 sens3 measur5 comput3 calculat3 \$2valuat3 examin5 test3 determin3 recogniz3 inspect3 anal5 monitor3 diagnos3 identif7) near3 ((bi\$1direction3 two\$1way two\$1direction both\$way both\$1direction ((two both) adj (way direction))) near2 current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 06:56
S75	318	S74 and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 06:57
S76	78	S75 and ((capacitor sampling) near4 (resist5 FET MOSFET BJT transistor))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 07:37
S77	6	S76 and (sampil3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 07:03
S78	133	S75 and (capacitor sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 07:43

S79	13	S78 and (sampl\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/16 07:27
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